



Neural Interfaces

NX-422

Manufacturing of
Neural Interfaces

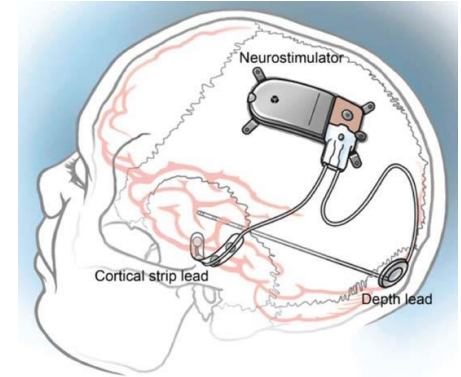
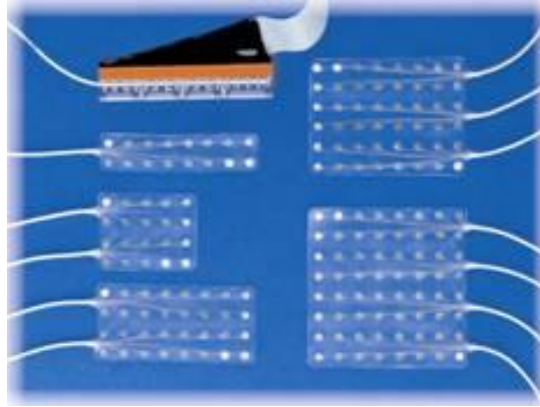
Giuseppe Schiavone

Neuro-X Institute

- Overview
- Silicon-based neurotechnology
- Flexible implantable neurotechnologies

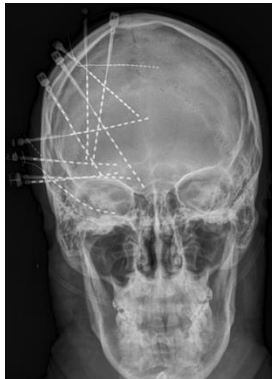
ECoG grids

Adtech

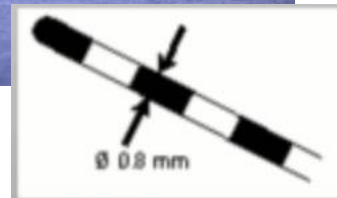
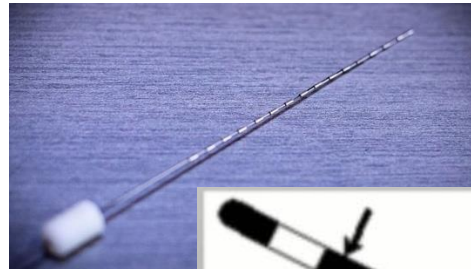


NeuroPace, USA

sEEG



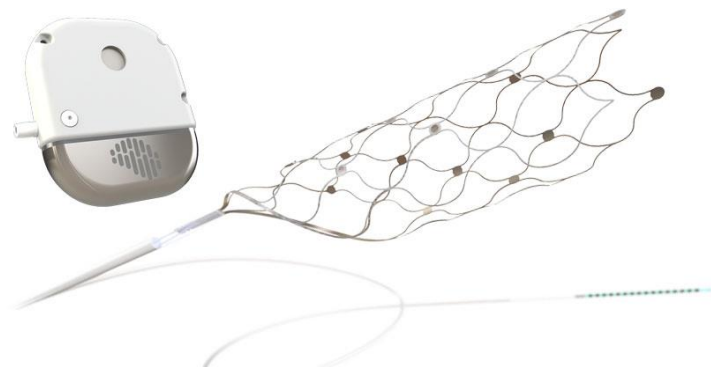
J Neurosurg Volume 123 • December 2015



Clinatec ECoG, CEA, France



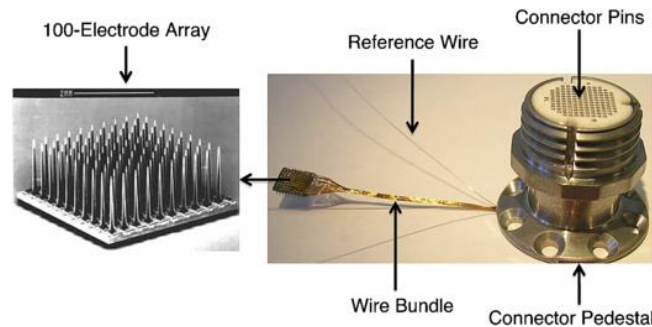
Invasive BCI / short-mid-term use in the clinic



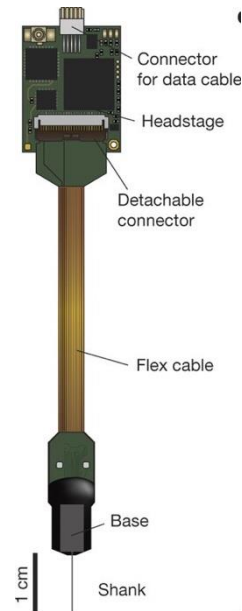
Synchron – stentrode

Utah array BrainGate

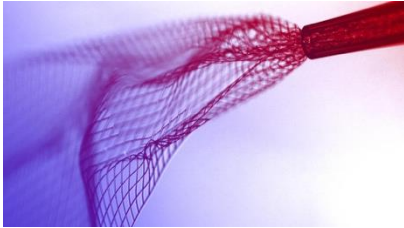
Blackrock Neurotech



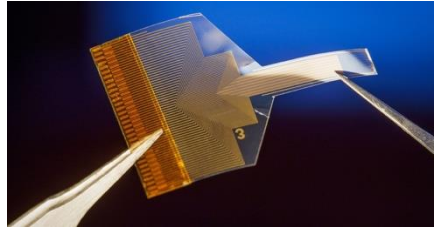
Neuropixel – IMEC Janelia



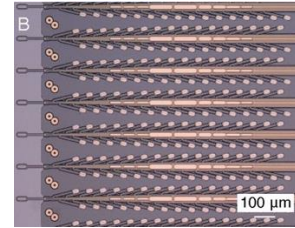
Miniaturised BCI



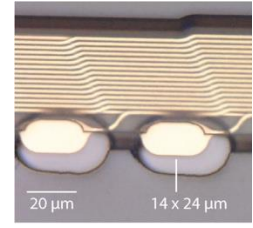
Nanomesh
Jia Liu - Harvard



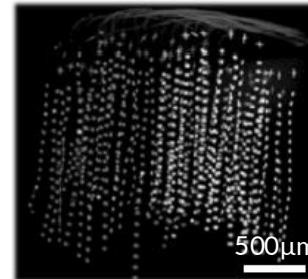
transparent ECoG
D Kuzum- UCSD



Neuralink



soft ECoG
SP Lacour – EPFL / Neurosoft Bioelectronics



NET 1'024 électrodes
L. Luan, Rice Univ.

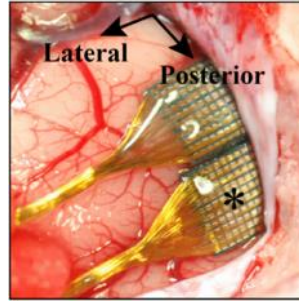


graphene electrodes
InBrain - Spain

All about connectors

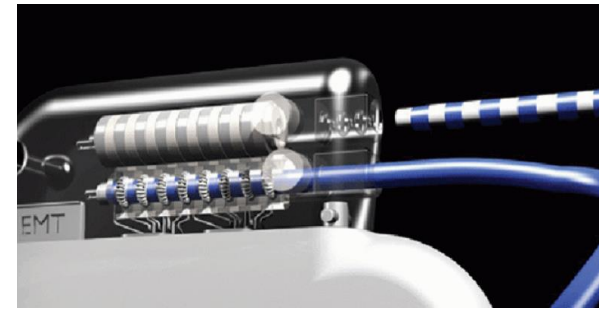


BrainGate

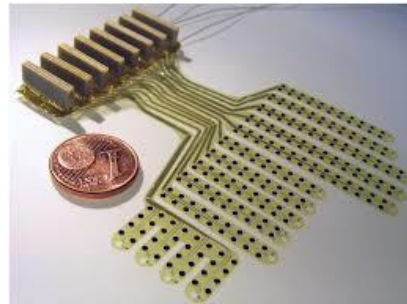


JNE | 2012 | 9(6)

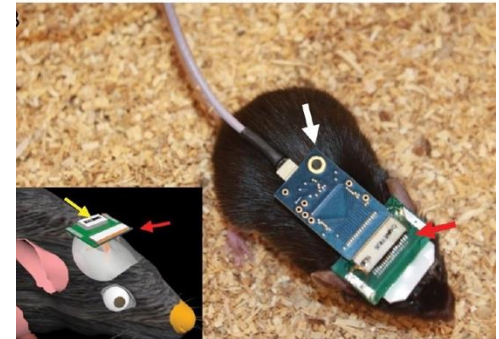
Transcutaneous interface
Wire bonding
Utah implant system



Bal seal Engineering Inc.

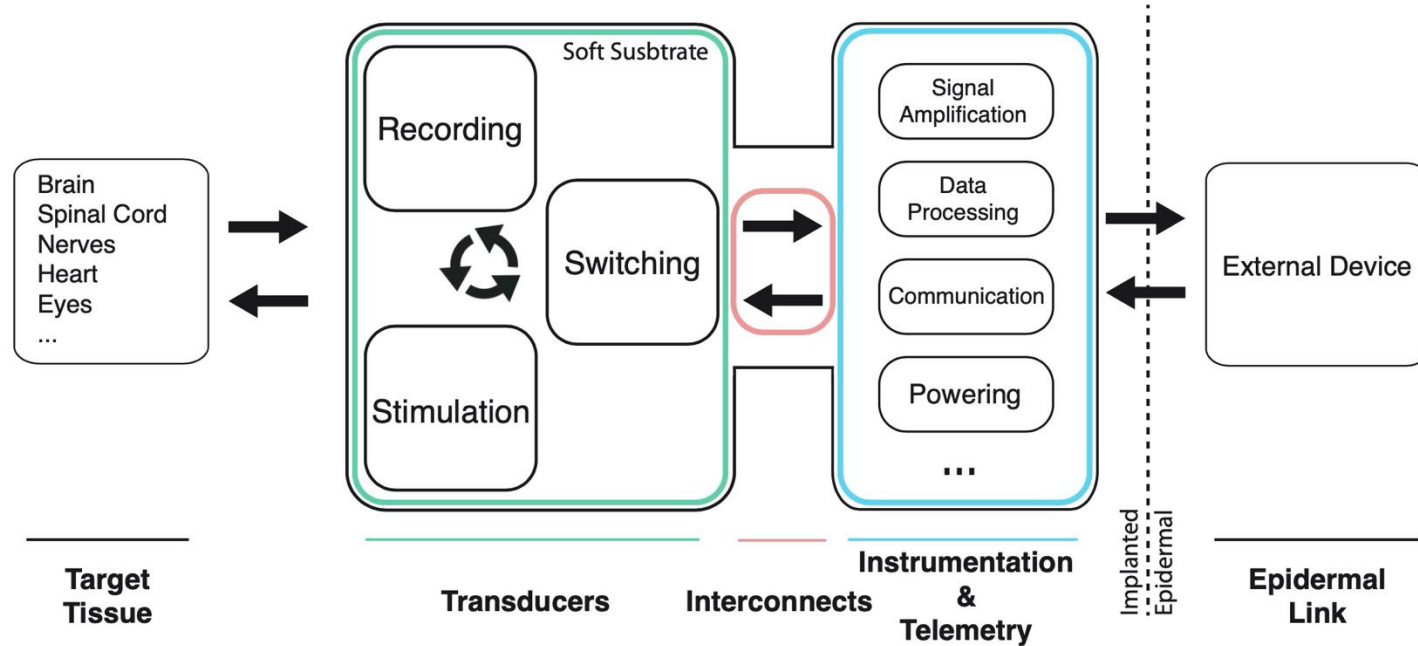


Flexible ECoGs
T. Stieglitz's lab



Nanomesh connector
C. Lieber

Architecture of an implantable bioelectronic system



Example

Neural interfaces

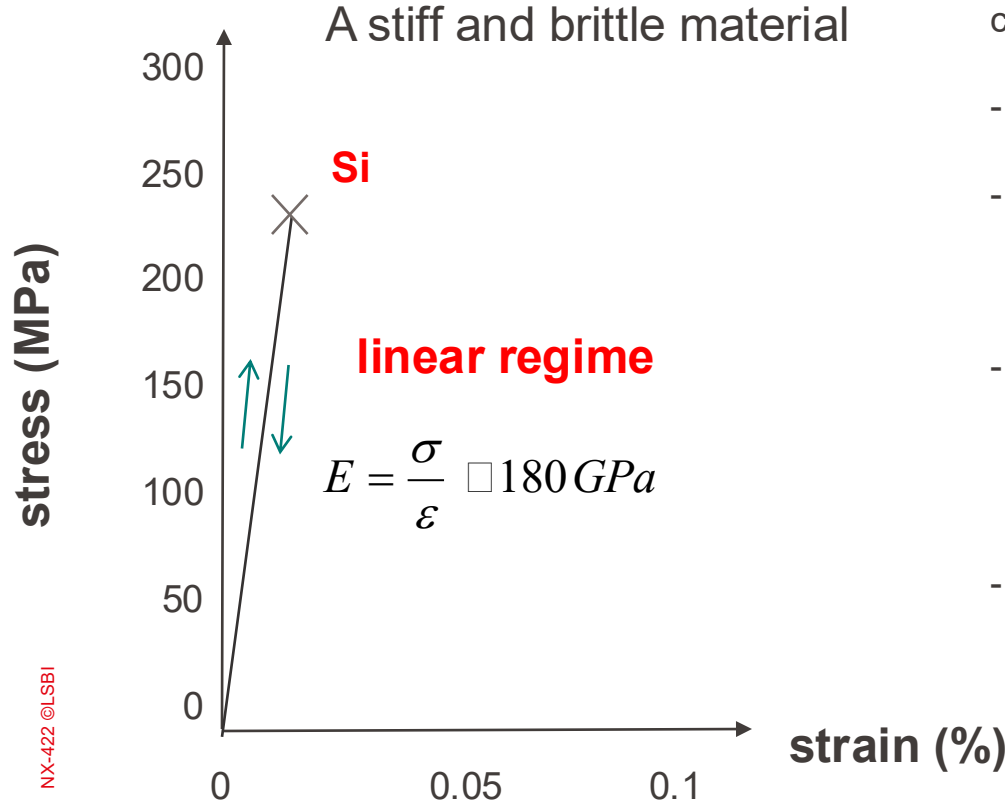
Interconnections

Implanted electronics

Hermetic packaging



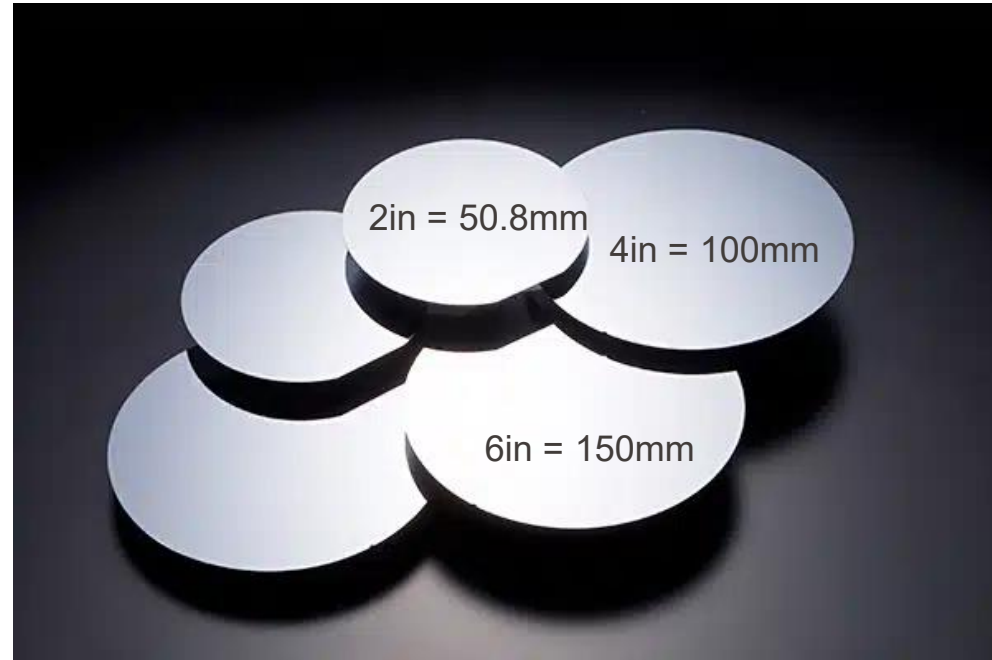
- Overview
- **Silicon-based neurotechnology**
- Flexible implantable neurotechnologies



“Inherited” from μ electronics because of the CMOS capabilities (doping)

- Excellent control over the mechanical properties.
- **Thermal stability:** High melting point and good thermal conductivity make it robust through high-temperature steps (oxidation, diffusion, anneals).
- **Surface chemistry control:** Surfaces can be precisely cleaned, passivated, and functionalized; Si/SiO₂/Si₃N₄ stacks are well understood for adhesion and protection.
- **Scale & cost:** Abundant material, mature equipment and supply-chain. Decades of CMOS know-how transfer directly to MEMS.

- diameter: 2in – 18in
- *12in: modern semicond. fab.*
- thickness: 275 - 1'000 μm
- flatness
- orientation flat and notch
- *(100) or (111) orientation*
(anisotropy in some properties)



Microfabrication in a Cleanroom a highly controlled environment

▪ Classification ISO

- ISO class 1: 10 particles per m³ (particles > 0.1µm)
- ISO class 5: 100'000 particles per m³ (particles > 0.1µm)

▪ Air filtration

▪ Temperature and humidity control

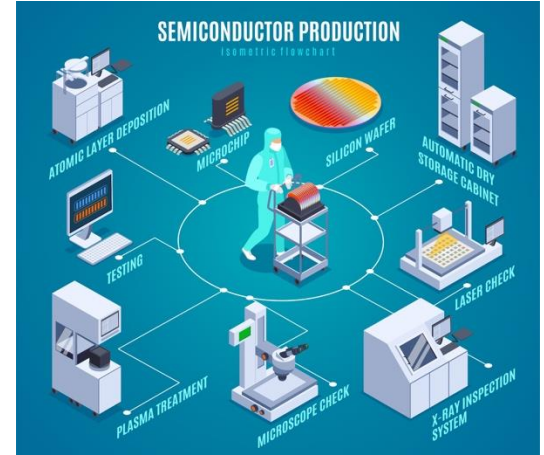
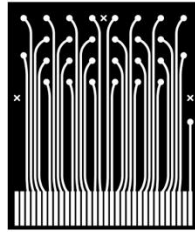
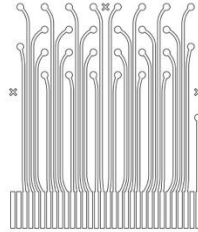
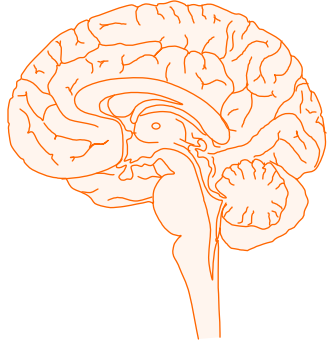
▪ Surface cleanliness

| Class | ≥0.1 µm | FED STD 209E equivalent |
|-------|-----------|-------------------------|
| | ISO 1 | |
| ISO 2 | 100 | |
| ISO 3 | 1,000 | Class 1 |
| ISO 4 | 10,000 | Class 10 |
| ISO 5 | 100,000 | Class 100 |
| ISO 6 | 1,000,000 | Class 1,000 |
| ISO 7 | c | Class 10,000 |
| ISO 8 | c | Class 100,000 |
| ISO 9 | c | Room air |

https://en.wikipedia.org/wiki/Cleanroom#ISO_14644-1_and_ISO_14698

Microfabrication in a Cleanroom a highly controlled environment





1. Imaging

2. Design

3. Manufacturing

Layer-by-layer fabrication – subtractive

- **Build 3D by stacking 2D.** Start with flat wafer, then add a thin film, pattern it, etch it, and repeat. Layer-by-layer steps turn flat patterns into 3D devices.
- **Add material.** Grow/deposit films (metals, SiO_2 , Si_3N_4), via thermal oxidation, CVD, PVD, ALD.
- **Pattern with lithography.** Spin photoresist, align to marks, expose (UV), develop → a temporary mask defining where the underlying layer stays or goes.
- **Transfer the pattern.** Remove material with etching (dry RIE for vertical sidewalls; wet for isotropic). For lift-off for metals, special litho before deposition.
- **Clean, inspect, control.** Strip resist, clean residues, and use metrology (ellipsometry, SEM, etc.) to ensure each layer is in spec.

Layer-by-layer fabrication – additive

- **Build 3D by stacking 2D.** Start with flat wafer, then selectively add thin (thick?) films where needed through a patterned mask.
- **Pattern mask with lithography.** Spin photoresist, align to marks, expose (UV), develop → a temporary mask that defines where the next layer goes.
- **Add material.** Grow/deposit films through the mask, via electrodeposition, printing, etc.
- **Clean, inspect, control.** Strip resist, clean residues, and use metrology (ellipsometry, SEM, etc.) to ensure each layer is in spec.

- **thin-films**

- metals
- insulators

- deposition

- evaporation
- sputtering
- ALD
- CDV...

- etching



sputterer



evaporator

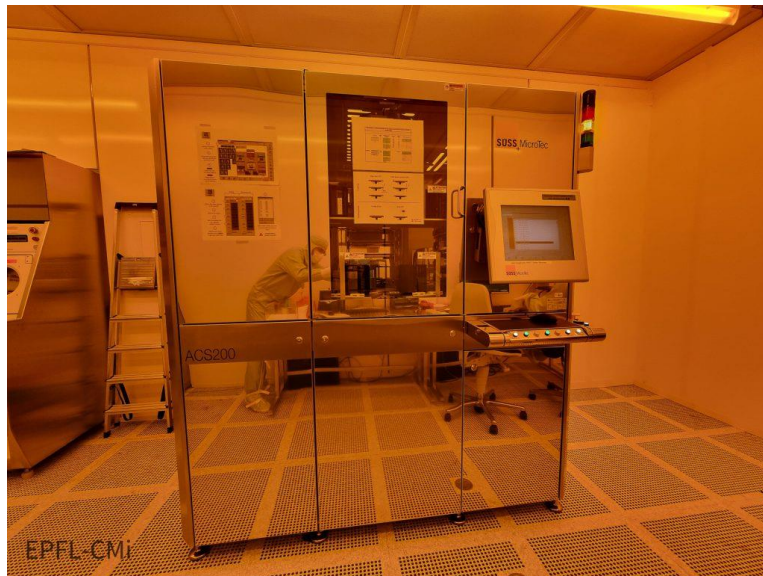
▪ photoresists

- positive
- negative

▪ parameters

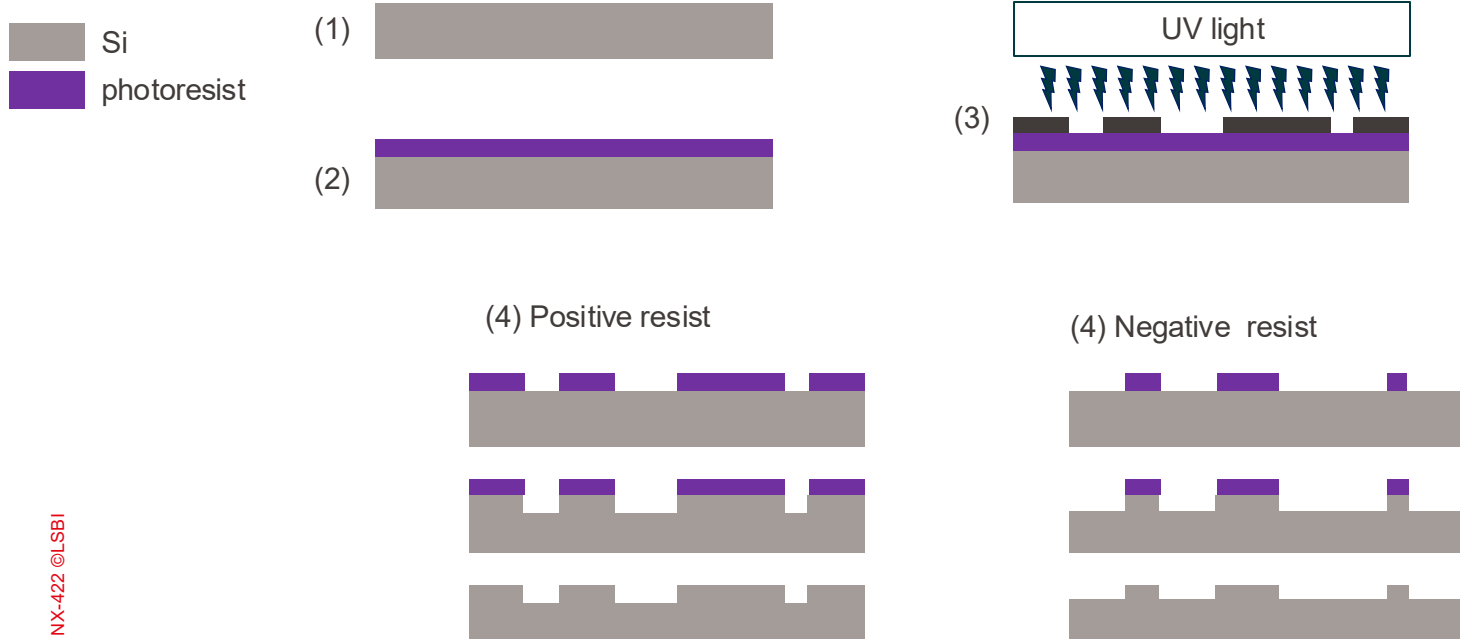
- Thickness range: 0.5 - 2 μm (thin)
- Thickness range: 2 - 100 μm (thick)
- spin-coating speed
- Sensitivity (dose needed)
vs resolution (smallest feature)

- Contrast (sharpness of transition btw soluble/insoluble)
- DUV to UV sensitive
- E-beam and X-ray
- Etch resistance
- Adhesion
- ...

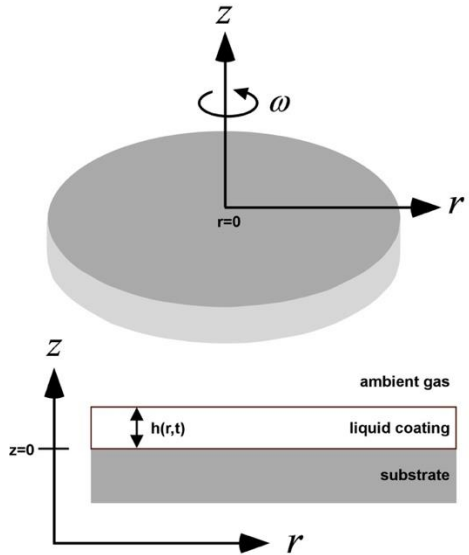


coater - developer

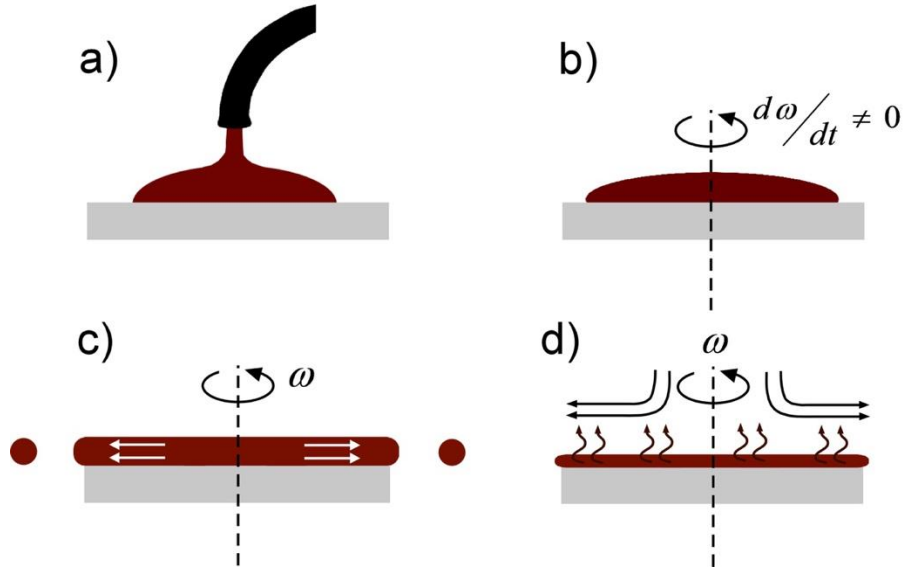
- Transfer of a geometric pattern through a photomask into a photosensitive polymer



Viscous fluid on a rotating disk



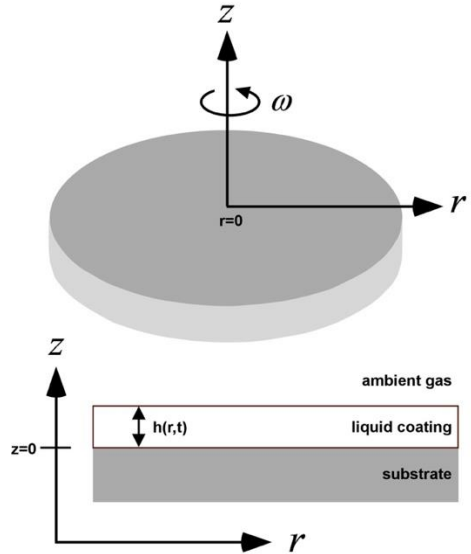
Dispense / Accelerate / Flow / Evaporate



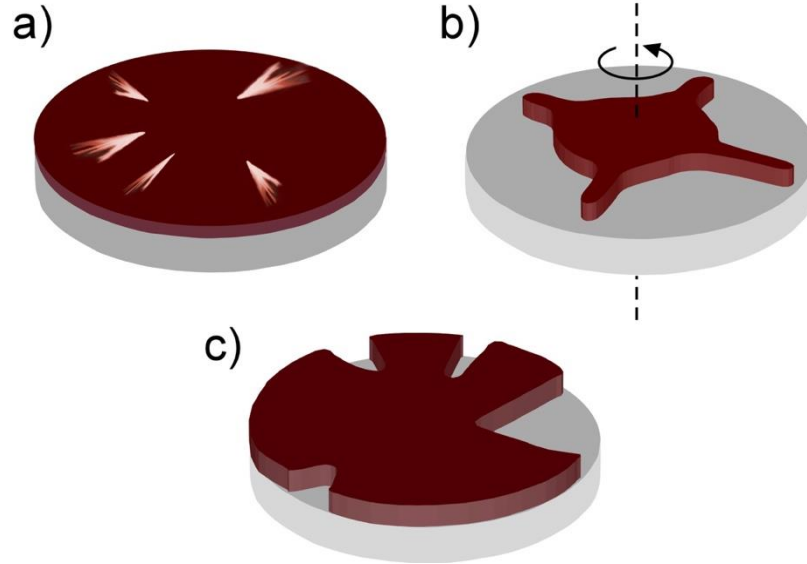
<https://www.youtube.com/watch?v=uv1A7qAqgRk>

Adapted from S.L. Hellstrom, Stanford University

Viscous fluid on a rotating disk



Deviation from ideal spin
Streaks / Non uniformity / uncoated areas

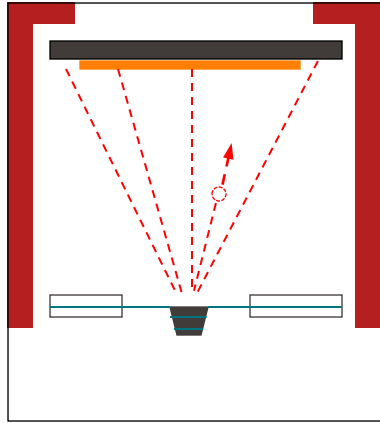


Goal: uniform thickness controlled by spin speed only (not time, volume, ...)

Process parameters:

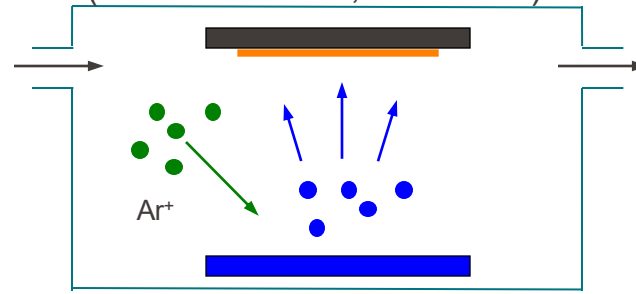
Pressure
Temperature
Deposition rate

Evaporation



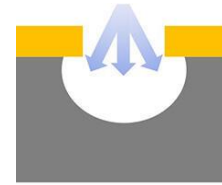
Sputtering

Also used for a wide range of inorganic materials (semiconductors, dielectrics)

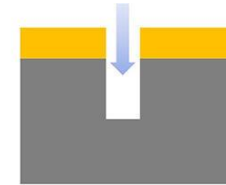


- Wet etching

- Selective, isotropic
- e.g. KOH for Si



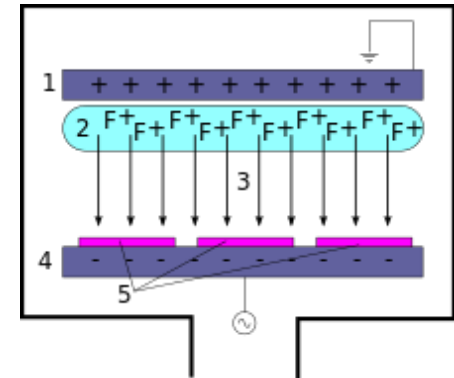
Isotropic Etching



Anisotropic Etching

- Dry etching

- usually selective, anisotropic
- e.g. reactive ion etching (RIE) (chemical + physical)
 - low-pressure plasma to remove material directionally
- (also vapour etch, no plasma)
→ see MEMS surface micromachining...



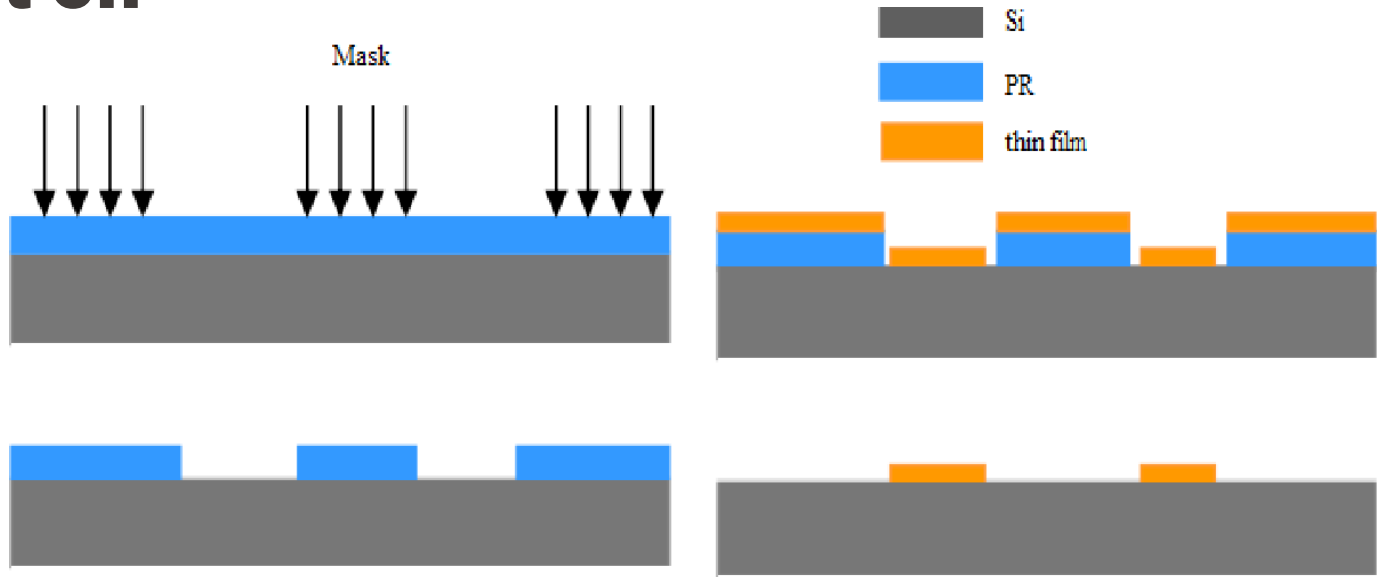
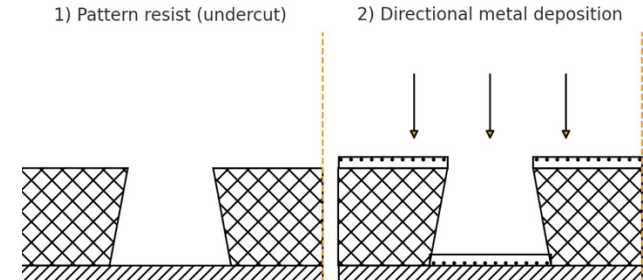
DOI:[10.51847/7tmarkoorg](https://doi.org/10.51847/7tmarkoorg)

Figure 1. Lift-off process

- Avoids etching step
- Requires careful photoresist profiling and ~directional (non-conformal) thin-film deposition



Some Typical processes

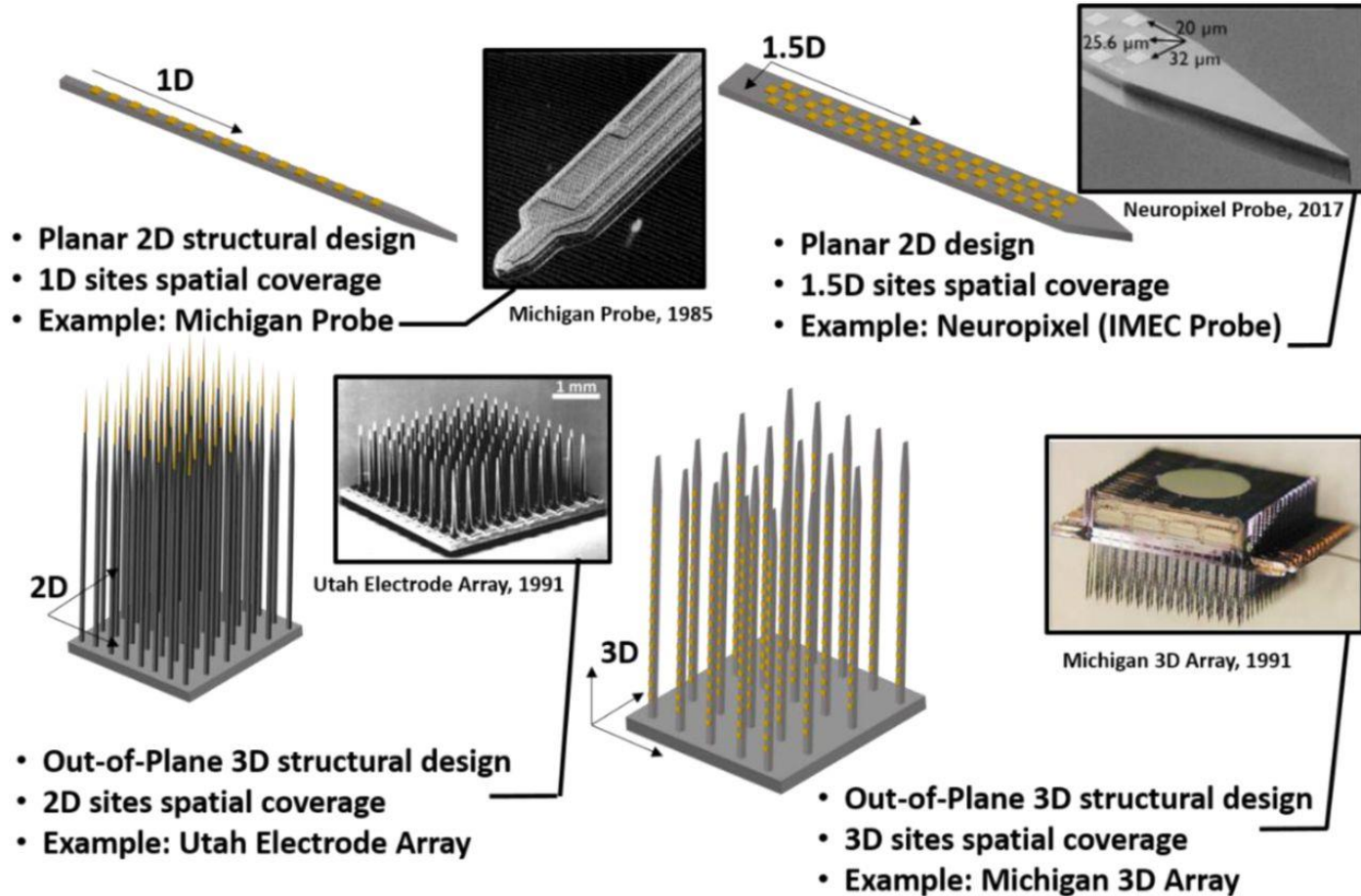
| Material | Thin-film deposition | Patterning (typical) | Notes |
|--|--|---|---|
| Silicon (Si) | <ul style="list-style-type: none"> • Epitaxial CVD ($\text{SiH}_4/\text{SiH}_2\text{Cl}_2 + \text{H}_2$) • LPCVD polysilicon • PECVD a-Si • Sputter/evap (amorphous) | <ul style="list-style-type: none"> • Dry: RIE/ICP (SF_6, HBr/Cl_2), DRIE (Bosch) for deep high-AR • Wet: KOH/TMAH (anisotropic), EDP (legacy), HNA ($\text{HF}-\text{HNO}_3-\text{CH}_3\text{COOH}$, isotropic) | Orientation matters for wet etch (e.g., {111} slow). Use hard masks for deep Si etches. |
| Silicon dioxide (SiO_2) | <ul style="list-style-type: none"> • Thermal oxidation (dry/wet) • LPCVD/PECVD/HDPCVD • ALD SiO_2 • Sputter/evap | <ul style="list-style-type: none"> • Dry: Fluorocarbon RIE ($\text{CF}_4/\text{CHF}_3/\text{C}_4\text{F}_8 + \text{O}_2$) • Wet: HF, BOE ($\text{HF}/\text{NH}_4\text{F}$) | Photoresist masks OK for short etches; for long/harsh etches use Si_3N_4 or metals as hard masks. |
| Gold (Au) | <ul style="list-style-type: none"> • Evaporation (e-beam/thermal) • Sputtering • Electroplating (needs seed) • Electroless Au (select chemistries) • (ALD exists but specialized) | <ul style="list-style-type: none"> • Patterning: Lift-off (preferred) • Wet etch: KI/I_2 or aqua regia • Dry/physical: Ion beam etch (IBE/milling); Cl_2/Ar RIE possible but tricky | Use Cr or Ti adhesion underlayers; wet etches attack Cr/Ti differently—plan the stack/removal order. |
| Platinum (Pt) | <ul style="list-style-type: none"> • Sputtering • E-beam evaporation • ALD Pt (e.g., $\text{MeCpPtMe}_3 + \text{O}_2$) • Electroplating (special baths) | <ul style="list-style-type: none"> • Patterning: Lift-off (common) • Physical: Ion beam etch/milling • Dry: Cl_2/Ar or halogen-based RIE (slow, process-sensitive) • Wet: Hot aqua regia/oxidizing halide mixes (slow) | Pt is hard to etch chemically; expect slower rates and more redeposition—plan for IBE or lift-off. |

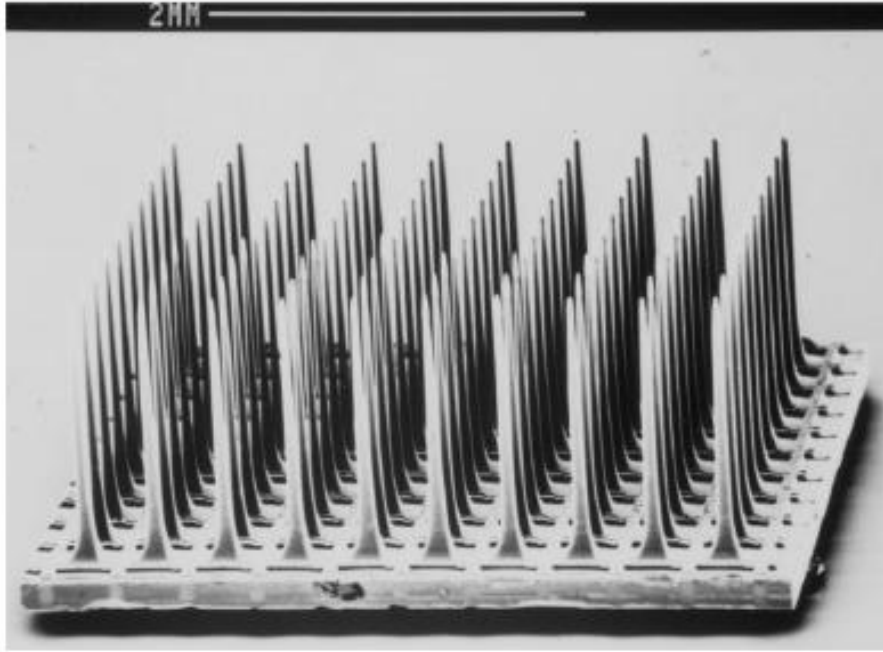
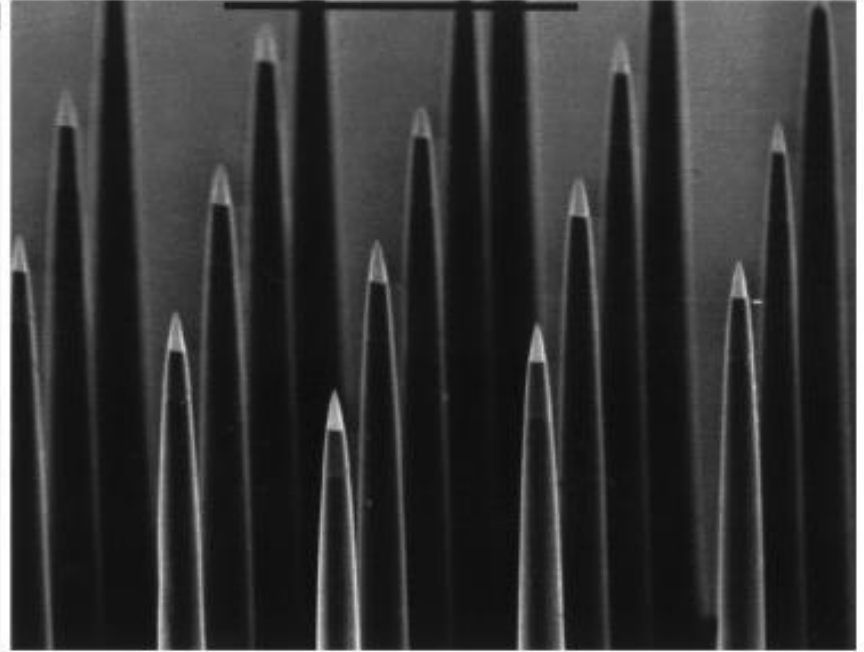
The process flow

a detailed sequence of steps and techniques

→ a roadmap outlining how various fabrication processing are combined to create the desired features on a silicon wafer

- **Recipe:** To define the roadmap.
- **Repeatability:** To ensure that devices are fabricated consistently with high yield.
- **Optimization:** To minimize defects and improve performance.
- **Documentation:** Provides a clear record of every step and parameter, essential for troubleshooting and improving processes.



**(a)****(b)**

a. Backside dicing

→ 10x10 0.5mm deep matrix

b. Glassing**c. Grinding****d. Back-side metallization**

→ Pt/TiW/Pt sputtering

e. Front-side dicing

→ 1.5mm deep columns

f. Wet etching→ HF:HNO₃ (1:19 ratio)**g. Tip metallization**

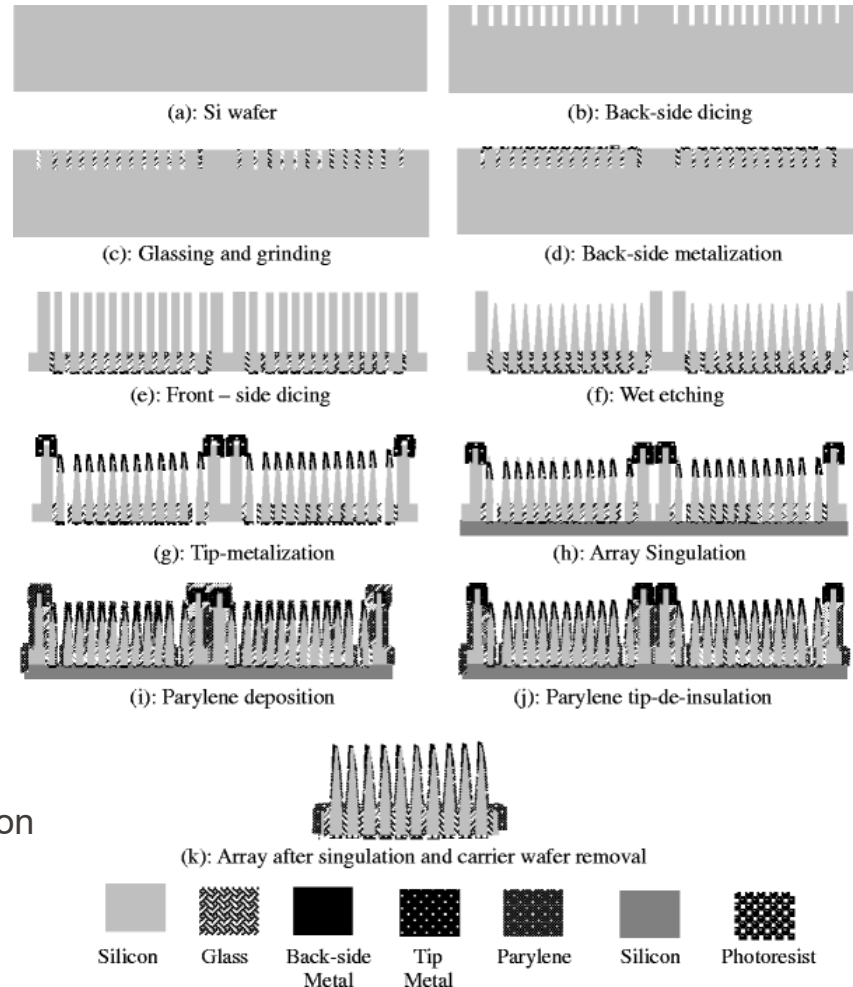
→ sputtered Ti/Ir then electrochem. activation

i. Parylene deposition

→ LPCVD, 3μm thick

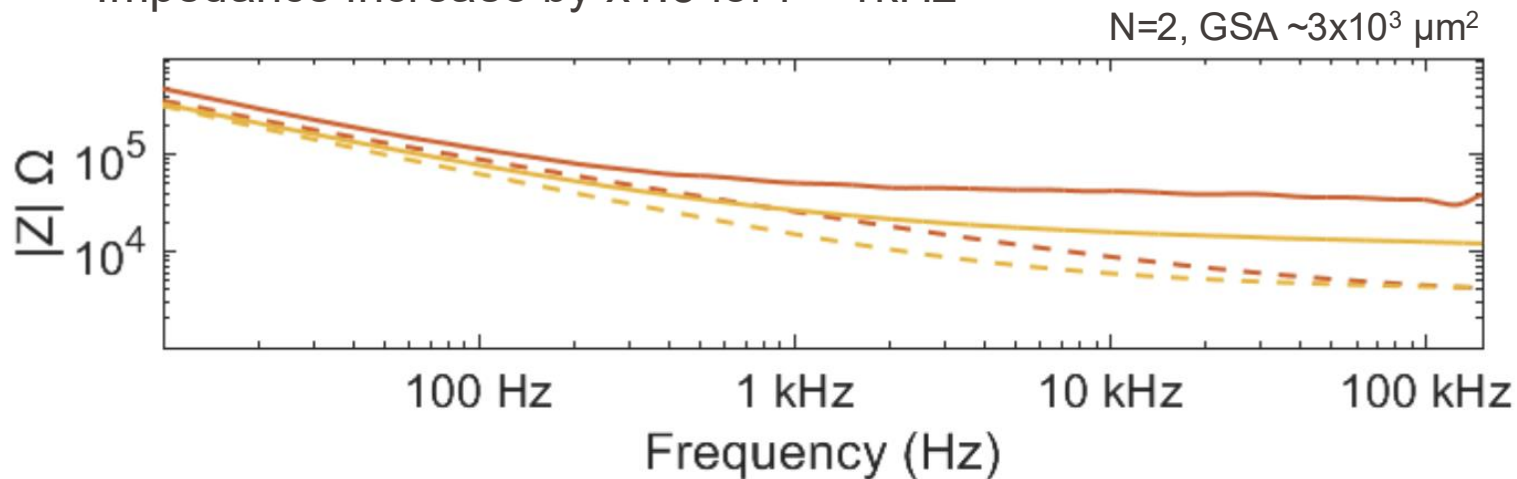
j. De-insulation

→ oxygen plasma etching, 30-350μm length



Measured impedance spectra

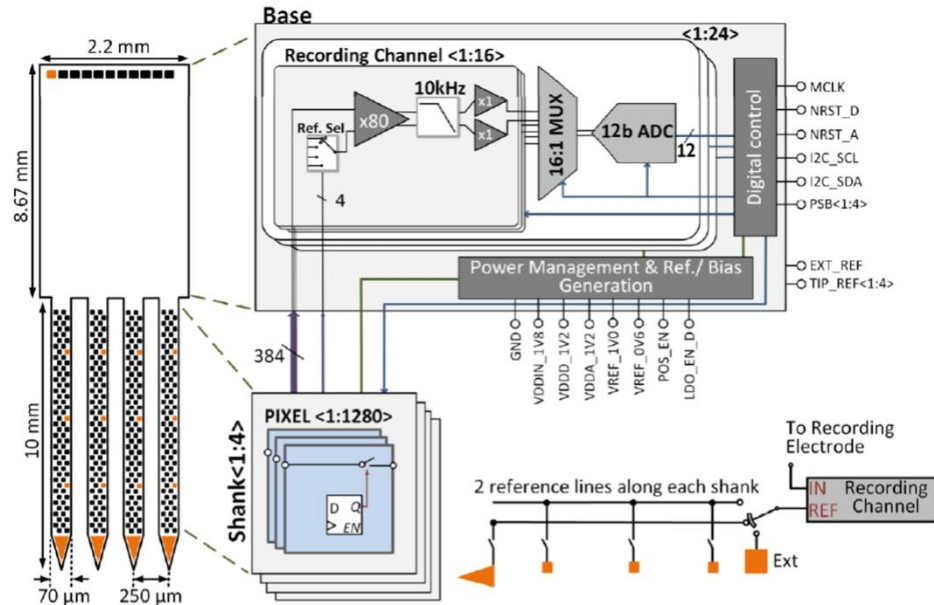
- In vitro electrodes (dashed)
- In vivo electrodes (plain)
- Impedance increase by x1.5 for $f > 1\text{ kHz}$



Active silicon probes

Neuropixel

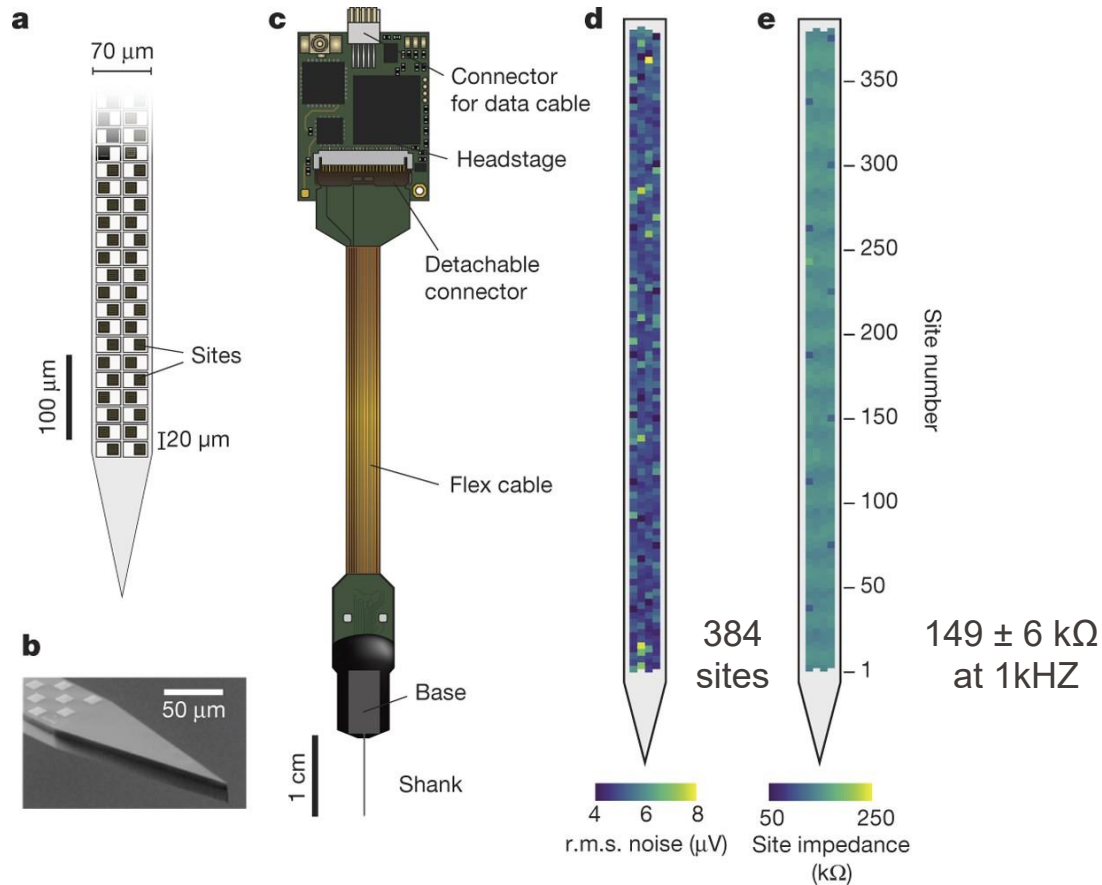
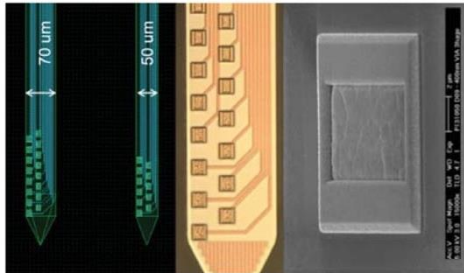
user-programmable switches that allow the recording channels to address 384 of the **960 total sites** simultaneously
130nm CMOS technology



Active silicon probes

Neuropixel

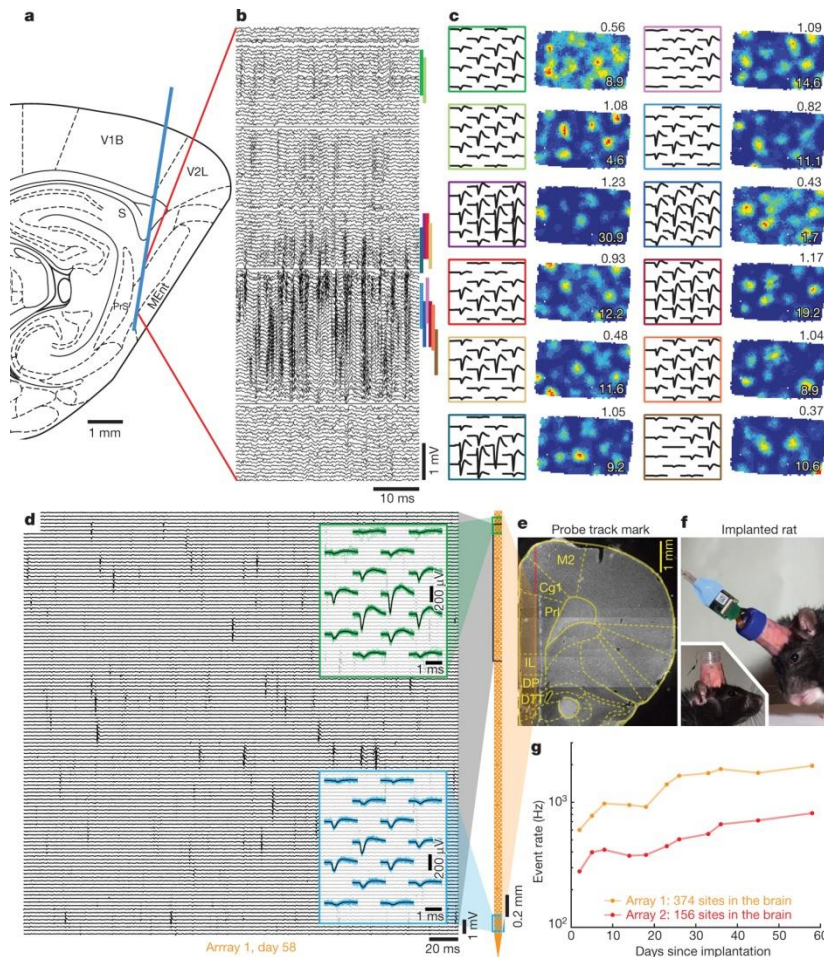
TiN coating
12 x 12 μm^2 contact



Active silicon probes

Neuropixel

Recordings from entorhinal and medial prefrontal cortices using chronic implants in unrestrained rats



- Silicon is a material of choice for microfabricated neural probes

- Leveraging MEMS/microelectronic microfabrication to
 - miniaturise probes
 - integrate on-board processing